

to relax the test conditions and decrease the SOA.

DOCUMENT CHANGE REQUEST

1278 DCR number Changes required for: General Originator: Steve Thacker Date: 2019/09/06 Date sent: 2019/06/12 Organisation: ESCC Executive Secretariat Status: IMPLEMENTED Title: TRANSISTORS, POWER, MOSFET, N-CHANNEL, Number: 1 5205/030 Issue: Other documents affected: Page: 7 Paragraph: 1.5 Note 1 Original wording: As per 5205/030 issue 1 Proposed wording: Safe Operating area figure for Variant 03 is amended; see attached mark-up specification 5205/030 Draft 2A for details. Note: several additional minor editorial changes are included including the addition of ESCC reference spec hyperlinks and internal paragraph cross-references. Justification: This DCR is raised at the request of supporting ESCCQPL Manufacturer Infineon who have stated the following in justification: 1. We noticed that the RDSon limit-line has been calculated with the RDSon value at room temperature, instead of the one at Tj(max). We would like to correct this.

2. The DC and 10ms curves are slightly overrated, therefore the SOA screening test conditions are too tight. We would like

Attachments:
escc5205030iss2_done.docx
Modifications:
N/A
Approval signature:
Duston Peru
Date signed:
2019-09-06